

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al Art Unit : 2891
Serial No. : 09/894,950 Examiner : Caridad Everhart
Filed : June 27, 2001 Conf. No. : 6263
Title : SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the reference listed on the attached PTO-1449 form.

The reference was cited in an office action for counterpart Japanese Patent Application No. 2001-192141. In that office action, the Examiner said the following:

Especially, refer to paragraph [0054] in JP 11-087726.

As described in JP 10-031235, it is well known at the time of the invention that capacitance is constituted by using the same layer as a light-shielding film.

Further, as described in JP 2000-010120, it is well known at the time of the invention that a gate signal line is constituted by using the same layer as a light-shielding film

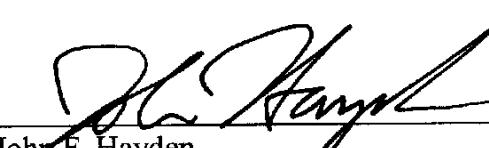
JP 11-087726 and JP 10-031235 are already of record in this application.

This statement is being filed with the filing of a request for continued examination.

Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 6/23/06


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Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-280001	Application No. 09/894,950
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al		
		Filing Date June 27, 2001	Group Art Unit 2891	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
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	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Sub-class	Translation
							Yes No
	AL	JP2000-010120	14 JAN 2000	JAPAN			FULL (automated translation)
	AM						
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	